

Semiconductor Tester

Application area

- Automatic production lines
- In-line systems
- Single or multisite test
- Research and development
- Verification of prototypes
- Production characterization
- Quality assurance and service

Measurement Methods, Standard Tests

- Contact test
- Short-circuit test
- Detailed parametric tests
- Automatic waveform test
- Digital scope function
- Analog and digital high
- Speed tests
- Parallel IC programming



Semiconductor-series production
IC multisite test with CT300 Meteor
parallel test of 32 chips



Semiconductor-series production
Use in German and Austrian international leading companies



CT300 Satellite



CT300 Meteor
for Prototype verification
and series production



Test of CMOS camera modules and image sensors

